VEECO DEKTAK 8M PROFILOMETER SOP

Revised April 2020

POWER UP

- 1. Log into the tool in your FOM account.
- 2. If system is not already on, turn **ON** the Dektak 8 by flipping the power switch located on the rear panel of the E-box connected to the profiler cover. See Fig. 1.



Fig 1. Power switch located on the rear panel of the E-box

- **3.** Turn the monitor **ON** by depressing the power button located on the front of the monitor in the lower middle.
- 4. Turn the computer **ON** by pressing the power switch located on the front of the computer.
- 5. Double click on the Dektak32 icon on the desktop or SELECT START>ALL PROGRAMS> DEKTAK32> Dektak32 from the Windows toolbar.
- 6. The Dektak 8 sample stage will initialize and the Start Screen Window will display.
- 7. Go to FILE/NEW to start a new scan.

SAMPLE LOADING

1. To load sample, move stage to the load/unload position by clicking the unload command

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in the stage control panel on the right side of the screen.

- 2. Open guard panel door.
- **3.** Load wafer onto stage, centering wafer on the vacuum stage, then turn on the vacuum via the toggle switch on left of Dektak 8 chassis.
- 4. Once wafer is mounted, click "YES" in the Load Sample dialog box (Fig. 2) to return stage to home position. The stage has finalized homing protocol when the output text in the lower left hand corner displays "READY".









- 5. Close guard panel door.
- 6. Press the **"TOWER DOWN TO NULL POSITION STYLUS UP"** icon. **This traverses** stylus to substrate surface, then releases stylus for additional positioning (without damaging stylus).

NOTE: Be aware of sample position with respect to stylus tip before lowering.

STANDARD SINGLE SCAN SEQUENCE

- **1.** Click on the scan routines window icon.
 - **a.** Adjust scan parameters by clicking any link (Fig. 3) to open scan parameters dialog box (Fig. 4).

Scan Parameters	
Scan Type:	Standard Scan
Scen_IR:	0
Locations	107614 µm, 114228 µm, 279.9*
lisan Lengthi	5864 µm
Scan Duration:	60 sec
Scan.Resolution:	0.326 um/sample
Meas Rangel	655kÅ
Etalua Forsa:	3 mg
Profiles	- <u>C</u> -
Rtdue Trees	Radius: 12.5 pm

Fig 3. Scan parameters window

b. Scan parameters, see Fig. 4:

ID - Filename desired

Stylus Type - 12.5 um radius tip (for note purposes only, does not affect scan)

Scan Duration - Time required completing scan from beginning to end

NOTE: The longer the scan duration, the more data points recorded and more time required for scan.

Scan Type - Standard Scan

Stylus Force - Force applied to substrate by stylus input range (0.7 to 15 mg)

NOTE: For soft materials (i.e. photoresist, polymers, soft metals, gold) use low force such as 1 to 2 mg

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D	Stylus Type	
2	Radius: 12.5 µm 💌	
incation c 107616 µm Y: 1	14223 µm T: 278.9 *	
ength Duration	Sample	
5864 µm 60	secs 18000 points	
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0.326 µm/sample	Standard Scan	
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rofile	Additional Parameters	
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Valeys -ur	Set foundoes	
⊙Hilsti¥aleys -℃	ě.	

Fig 4. Scan parameters dialog box

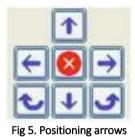
NOTE: For hard materials (i.e. chrome, nickel, silicon, glass) use higher force such as 10 to 15 mg

Measurement Range - Four step ranges, 1 mm, 2620 kA (286.6 um), 655 kA (65.5 um), 65 kA (65.5 um)

Profile - Hills, Valleys, or Hills & Valleys, depending on feature geometry



- c. Click OK.
- 2. Return to the Sample Positioning Window by clicking the Sample Positioning Window icon.
- 3. Move to desired start position on sample by either:
 - a. Left clicking in view window and moving the stage with the mouse
 - **b.** Using the positioning arrows (Fig 5) in the stage control panel.



- 4. Go to EDIT/DEFINE SCAN LOCATION, to input your start scan position. Click ENTER and close.
- 5. Go to EDIT/DEFINE SCAN LENGTH
 - **a.** Using the mouse move to the desired endpoint of scan, keep in mind that the motion of this move is unidirectional (i.e. left/right motion in the viewing window)
 - **b.** Left click mouse to define endpoint
 - c. Click ENTER and close.
- 6. Run the programmed Standard Scan.



3D MAP SCAN SEQUENCE

- **1.** Click on scan routines window icon.
 - **a.** Adjust scan parameters by clicking any link (Fig. 6) to open scan parameters dialog box (Fig.7)

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Stan Turai Standard Scan Stan LD: 0 Location: 107616 µm, 114223 µm Bran Length: 5844 µm Stan Duration: 60 sec Stan Resolution: 0.326 µm/sample Maar Ranga: 6556Å Styles Farce: 3 mg Profile: -\	
Location: 107616 µm, 114223 µm Bran Length: 5664 µm <u>Scan Duration:</u> 60 sec <u>Scan Recelution:</u> 0.326 µm/sample <u>Meas Range:</u> 6558Å <u>Stylus Force:</u> 3 mg	
Esan Lengthá 5864 µm <u>Sran Duration:</u> 60 sec <u>Sran Resolution:</u> 0.326 µm/sample <u>Meas Range:</u> 655kÅ <u>Stylus Force:</u> 3 mg	
Scan Duration: 60 sec Scan Revolution: 0.326 um/sample Meas Rangal: 655kÅ Stylus Force: 3 mg	s, 278.9°
Szan Resolutions 0.326 um/sample Meas Rangel 655kÅ Stylus Forces 3 mg	
Mear Rangel 655kÅ <u>Stylus Forcel</u> 3 mg	
<u>Styluz Forces</u> 3 mg	
Erefile: -T_r	
Stylus Type: Radius: 12.5 µm	

Fig 6. Scan parameters window

b. Scan parameters:

ID Filename

Stylus Type - 12.5 um radius tip (for note purposes only, does not affect scan)

Scan Duration - Time required completing scan from beginning to end

Scan Type - Map Scan

Stylus Force - Force applied to substrate by stylus input range (0.7 to 15 mg)

NOTE: For soft materials (i.e. photoresist, polymers, soft metals, gold) use low force such as 1 to 2 mg.

NOTE: For hard materials (i.e. chrome, nickel, silicon, glass) use higher force such as 10 to 15 mg.

Measurement Range - Four step ranges, 1 mm, 2620 kA (286.6 um), 655 kA (65.5 um), 65 kA (6.5 um)

ID	Stylus Type
3	Radus: 12.5 µm
Location	
107616 µm Yi 11	14223 µm T: 278.9 *
Length Duration	Sample
5864 µm 60	secs 18000 points
Resolution	Scan Type
0.326 µm/sample	Standard Scan
Rylus Force	Meas Range
3 mg 29.4 µN	6551Å 💉
Profile	Additional Parameters
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	Solt Tracodoin
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Hilsä¥alleys −Lr	

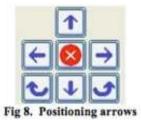
Fig 7. Scan parameters dialog box

Profile - Hills, Valleys, or Hills & Valleys, depending on feature geometry

- c. Click OK.
- 2. Return to the Sample Positioning Window by clicking the Sample Positioning Window icon.



- 3. Move to desired start position on sample by either:
 - **a.** Left clicking in view window and moving the stage with the mouse.
 - **b.** Using the positioning arrows (Fig 8) in the stage control panel.



4. Go to EDIT/DEFINE MAP AREA

- **a.** Move to the desired X direction endpoint (Left/Right unidirectional motion in view window).
- **b.** Left click in view window to define point.
- **c.** Move to the desired Y direction endpoint (Up/Down unidirectional motion in view window).

- d. Left click in view window to define point.
- e. Map Parameters dialog opens (Fig 9).
- 5. Input:
 - a. Lateral parameters # profiles, this depends on desired resolution and feature size (min. resolution = 1 um).
 - b. Choose desired image resolution.
 - c. Check Re-Null Tower under Additional Parameters.

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- 7. To analyze map scan:
 - **a.** Minimize Dektak32 window.
 - b. Open Vision software by double clicking on icon on

desktop.

c. Go to FILE/OPEN stored dataset

SAMPLE UNLOADING

1. To unload sample, move stage to the load/unload position by clicking the unload command

button whe stage control panel on the right side of the screen.

- 2. Open guard panel door.
- 3. Turn the vacuum OFF via toggle switch on left of Dektak 8 chassis and remove sample.
- 4. Close guard panel door.
- 5. Once sample is removed, click "YES" in the Load Sample dialog box to return stage to home position. The stage has finalized homing protocol when the output text in the lower left hand corner displays "READY".
- 6. Logout from the tool in your FOM account.

minal Parameters	Map P	arameters
Lateral Paramete	rs.	
Y Extent:	60	um.
Profiles:	60	
Resolution:	1	µm/scan
Image Resolution		
Best (100* Additional Param		
Balanced (Best (100*		
Re-nul To	wer	